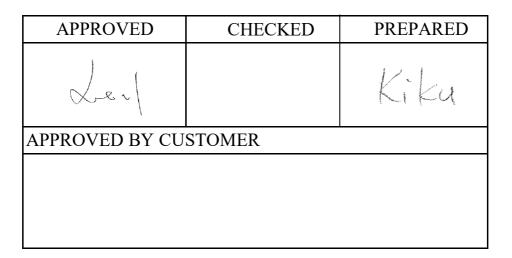
APPROVAL SHEET

Customer Name	:	
Customer P/N	:	
Frequency	: 54.000000 MHz	
Aker Approved P/	N: CXAN-054000-A-AL-00	
Aker MPN	: CXAN-054000-A-AL-00	
Rev.	:1	
ISSUE DATE	: Feb.23.2024	



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Web: www.aker.com.tw

MSL:Level 1 RoHS compliance

Ac	ccurate Kinetic Energy

Aker Approved P/N :		CXAN-0540	000-A-AL-00
APPROVED :	:	Xtal	SHEET : 1 of 9
PREPARED	•	Kiku	REV. : 1
			Confidential

Rev.	Date	Reviser	Revise contents
1	2024/2/23	Kiku	Initial Released



Aker Approved P/N	:	CXAN-054000-A-AL-00				
APPROVED	:	Xtal	SHEET : 2 of 9			
PREPARED	:	Kiku	REV. : 1			
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SMD CRYSTAL SPECIFICATION

1. ELECTRICAL CHARACTERISTICS

■ Standard atmospheric conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurement and tests are as follow :

Ambient temperature : 25±5°C

Relative humidity : 40%~70%

If there is any doubt about the results, measurement shall be made within the following limits:

Ambient temperature : 25 ± 3 °C

Relative humidity : 40%~70%

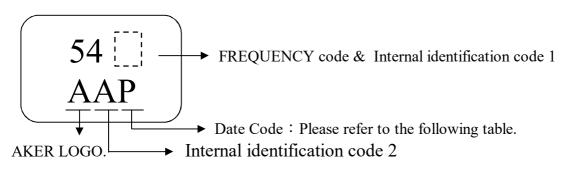
- AKER Model : CXAN-211
- Oscillation Mode : Fundamental
- Cutting Mode : AT CUT
- Measurement Equipment : 250B(Measured FL)
- Insulation Resistance : More than 500M ohms at DC 100V

		Electrical Spec						
Parameters	Symbol	Min.	Тур.	Max.	Units.	Notes		
Nominal Frequency	FL	54	4.00000	0	MHz			
Frequency Tolerance			±30		ppm	at $25^{\circ}C \pm 3^{\circ}C$		
Frequency Stability		±30			ppm	Operating Temp (Refer 25°C)		
Load Capacitance	CL		20		pF			
Aging			±3		ppm	First Year at 25°C		
Operating Temperature		-40	\sim	85	°C			
Storage Temperature Range		-55	\sim	125	°C			
Drive Level	DL			100	uW			
Equivalent Series Resistance	ESR			60	Ω	@Series		
Shunt Capacitance	C0			3	pF			
Please kindly be noted that AKI	ER DO NOT	Г guarant	ee parts c	uality wł	nich involv	ves human security application.		



Aker Approved P/N	:	CXAN-0540)00-A-AL-00
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2. MARKING :



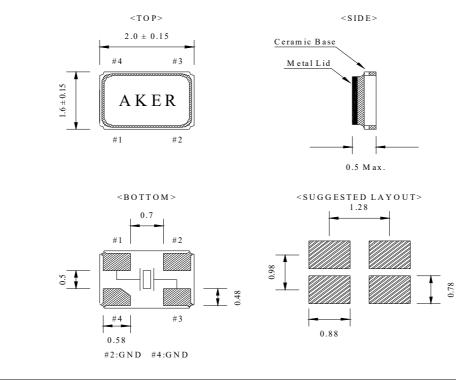
Date Code Table

	Month Year		1	2	3	4	5	6	7	8	9	10	11	12
2019	2023	(4N+3)	Α	В	С	D	Е	F	G	Н	J	Κ	L	М
2020	2024	(4N+0)	Ν	Р	Q	R	S	Т	U	V	W	Х	Y	Ζ
2021	2025	(4N+1)	а	b	С	d	е	f	g	h	j	k	I	m
2022	2026	(4N+2)	n	р	q	r	S	t	u	V	W	Х	у	Z

A cycle every four years

3. DIMENSION :

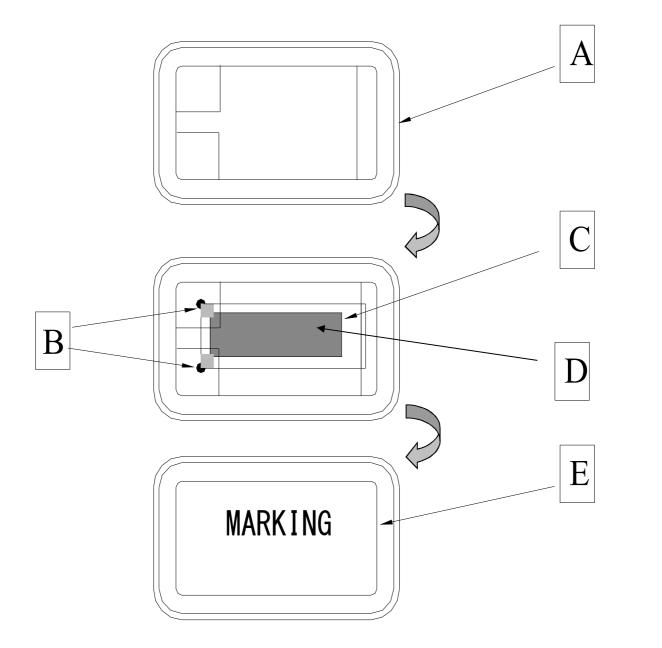
(Unit:mm)



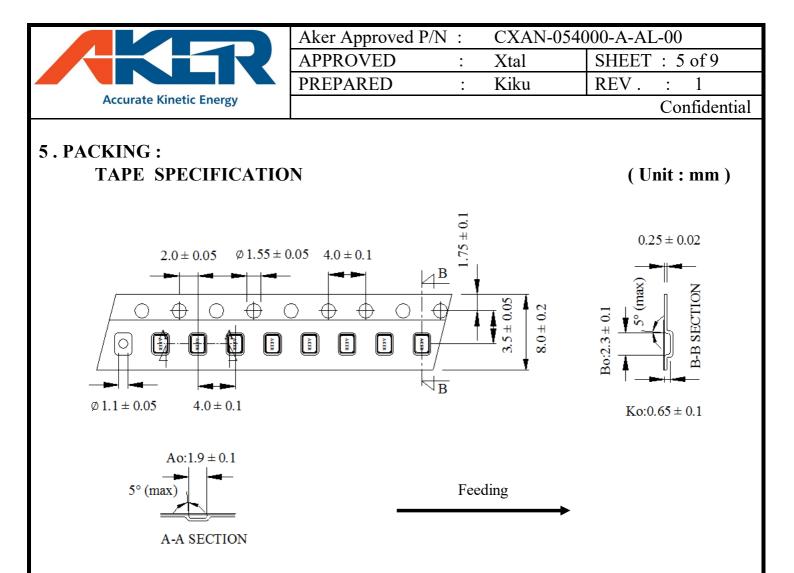


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APPROVED :	:	Xtal	SHEET : 4 of 9
PREPARED :	:	Kiku	REV. : 1
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4. STRUCTURE ILLUSTRATION

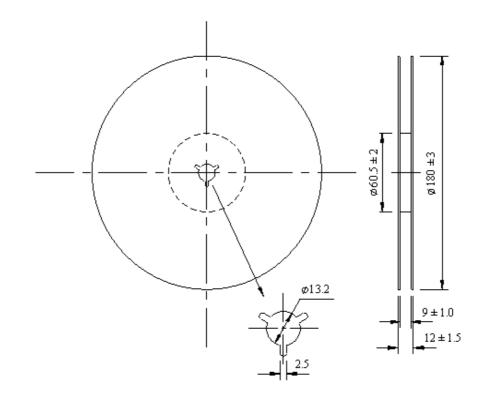


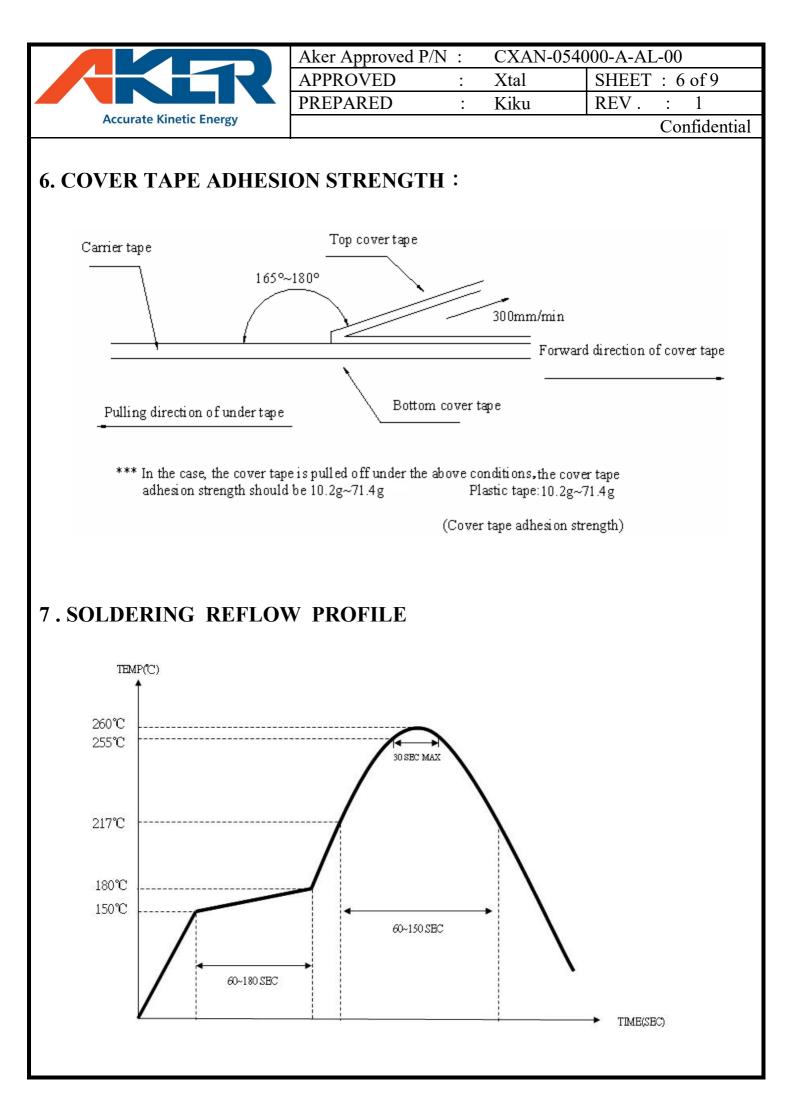
	COMPONETS	MATERIALS	CO	MPONENTS	MATERIALS
А	Base(Package)	Ceramic(Al2O3)+Kovar(Fe/Co/Ni)	D	Electrode	Noble metal
в	Conducitive adhesive	Ag / Silicon resin	E	Lid	Fe/Co/Ni
с	Crystal blank	SiO2			

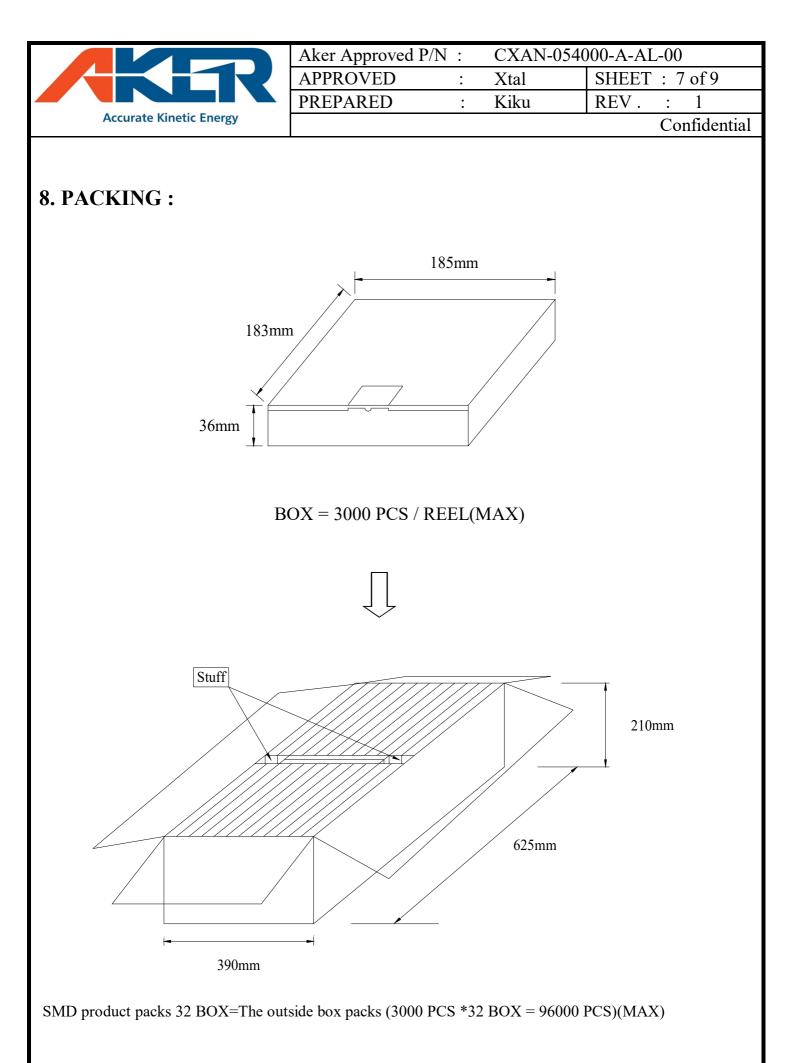


OUTLINE DIMENSION

(Unit:mm)









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9. MECHANICAL PERFORMANCE

TEST ITEMS	TEST METHODS AND TEST CONDITION	PERFORMANCE
9.1 Drop Test	The specimen is measured for its frequency and resistance before the test. It is then dropped from a hight of 75 cm or more as a free fall object onto a hard wooden plate of 30mm or more in thickness. (in accordance with JIS-C0044)	
9.2 Vibration Test	The specimen is measured for its frequency and resistance before the test. Most them into X,Y and Z axes, respectively, for the vibration test. Vibration condition: Frequency range ; $20 \sim 2000$ HZ Peak to peak amplitude : 1.52 mm Peak acceleration : $20G$ Sweep time : 20 minute / axis Pendicular total test time : 4 hours	To satisfy the electrical performance .
9.3 Resistance to Soldering Test	(in accordance with MIL-STD-883F : 2007.3) The specimen is measured for its frequency and resistance before the test. Place the specimen on the belt of the converynace and let it pass through the reflow with the presetted temperature condition. After passing twice the reflow place, the specimen under the referee condition for -~2 hours and then measure its electrical performance. Temperature Condition of IR Simulation: The temperature range of the preheated section is setted at $150 \sim 180^{\circ}$ C for $60 \sim 120$ sec. For the next section the temperature range is setted at $217 \sim 260^{\circ}$ C for $45 \sim 90$ sec. and within this time range the specimen should be able to sustain at the peak temperature, $260 \pm 73^{\circ}$ C , for 10 sec long. (in accordance with JESD22-B106-B)	
9.4 Fine Leak Test	Place the specimen in a pressurized container and pressurize it with the detection gas (mixed gas consisting of 95% or more helium) for at least 2 hours. Complete the measurement of the concentration of helium within 30 min after taking it out from the pressurized container. (in accordance with MIL-STD-883F : 1014.11)	Less than 1.0 * 10 ⁻⁸ atm .c.c. / sec, Helium
	The referee condition . Temperature 25 ± 2 °C Humidity $44 \sim 55$ % Pressure $86 \sim 106$ kPa (in accordance with MIL-STD-883E : 1014. 9)	1



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PREPARED	:	Kiku	REV. : 1
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10. CLIMATIC RESISTANCE

TEST ITEMS	TEST METHODS AND TEST CONDITION	PERFORMANCE			
10.1 Low Temp Exposure Test	The specimen is measured for its frequency and resistance before the test . Place the specimen in the chamber and kept it at the temperature of $-40 \pm 3^{\circ}$ C for 168 ± 6 hours . Take the specimen out of the chamber and measure itselectrical performance after leaving $1 \sim 2$ hours under the referee condition. (in accordance with JIS-C0020)				
10.2 Aging Test	The specimen is measured for its frequency and resistance before the test . Place the specimen in the testing chamber and keep it at the temperature of $+ 125 \pm 3^{\circ}$ C for 720 ± 48 hours. And then take the specimen out of the chamber and measure its electrical performance after leaving for $1 \sim 2$ hours under the referee condition . (in accordance with JIS-C0021)	To satisfy the electrical performance .			
10.3 High Temperature & High Humidty	The specimen is measured for its frequency and resistance before the test . Place the specimen in the testing chamber and kept it at the temperature of $+85 \pm 5$ °C and humidity of 85 ± 5 % for 168 ± 6 hours.and then take the specimen out and measure its electrical performance after leaving for $1 \sim 2$ hours under the referee condition. (in accordance with MIL-STD-883F : 1004.7)				
10.4 Temperature Cycle Test	The specimen is measured for its frequency and resistance before the test . Subject the specimen to the 100 cycles of temperature ranges stated below . High temp . + 125 ± 3 °C (15± 3 min). $2\sim3$ min. $2\sim3$ min. Low temp55 ± 3 °C (15± 3 min). Measure its electrical performance after leaving it for 1 ~ 2 hours under the referee condition . (in accordance with MIL-STD-883F : 1010.8)				

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